21. PETERSON, J. J., *A Posterior Predictive Approach to Multiple Response Surface Optimization* . . . . . April, 139–153
22. PRESCOTT, P. AND DRAPER, N. R., *Mixture Component-Amount Designs Via Projections, Including Orthogonally Blocked Designs* . . . . . October, 413–431
23. REYNOLDS, JR., M. R. AND STOUMBOS, Z. G., *Should Observations Be Grouped for Effective Process Monitoring?* . . . . . October, 343–366
24. ROBINSON, T. J.; MYERS, R. H.; AND MONTGOMERY, D. C., *Analysis Considerations in Industrial Split-Plot Experiments with Non-Normal Responses* . . . . . April, 180–192
25. ROMANO, D.; VARETTO, M.; AND VICARIO, G., *Multipleresponse Robust Design: A General Framework Based on Combined Array* . . . . . January, 027–037
26. SHU, L.; TSUNG, F.; AND TSUI, K.-L., *Run-Length Performance of Regression Control Charts with Estimated Parameters* . . . . . July, 280–292
27. WEBB, D. F.; LUCAS, J. M.; AND BORKOWSKI, J. J., *Factorial Experiments When Factor Levels Are Not Necessarily Reset* . . . . . January, 001–011
28. WILSON, A.; HAMADA, M.; AND XU, M., *Assessing Productin Quality with Nonstandard Measurement Errors* . . . . . April, 193–206
29. WOODALL, W. H.; SPITZNER, D. J.; MONTGOMERY, D. C.; AND GUPTA, S., *Using Control Charts to Monitor Process and Product Profiles* . . . . . July, 309–320
30. ZHANG, L. AND CHEN, G., *EWMA Charts for Monitoring the Mean of Censored Weibull Lifetimes* . . . . . July, 329–335

DEPARTMENTS

Book Reviews

Case Studies in Reliability and Maintenance by W. R. Blischke and D. N. P. Murthy, eds. . . . . S. E. RIGDON October, 452–454
Handbook of Statistics 22: Statistics in Industry by R. Khattree and C. R. Rao, eds. . . . . T. P. RYAN July, 339–341
Improving Healthcare with Control Charts: Basic and Advanced SPC Methods and Case Studies by R. G. Carey . . . . . W. H. WOODALL July, 336–338
Methods of Multivariate Analysis, 2nd ed. by A. C. Rencher . . . . . C. M. BORROR January, 125–126
Multivariate Statistical Process Control with Industrial Applications by R. L. Mason and J. C. Young . . . . . C. W. CHAMP January, 126
Planning, Construction, and Statistical Analysis of Comparative Experiments by F. G. Giesbrecht and M. L. Gumpertz . . . . . T. P. RYAN October, 454–457
Quality Control, 7th ed. by D. H. Besterfield . . . . . L. S. NELSON April, 241–242
Semiparametric Regression by D. Ruppert, M. Wand, and R. Carroll . . . . . T. P. RYAN April, 242–243
Statistical Models and Control Charts for High-Quality Processes by M. Xie, T. N. Goh, and V. Kuralmani . . . . . L.-Y. CHAN April, 240–241
Statistical Methods for Six Sigma: In R&D and Manufacturing by A. M. Joglekar . . . . . R. NEAGU July, 338–339
Statistical Thinking: Improving Business Performance by R. Hoerl and R. D. Snee . . . . . C. A. LAWSON January, 126–128
Weibull Models by D. N. P. Murthy, M. Xie, and R. Jiang . . . . . J. I. MCCOOL October, 451–452

Book Reviewers

Borror, C. M. . . . . January, 125–126
Champ, C. W. . . . . January, 126
Chan, L.-Y. . . . . April, 240–241
Lawson, C. A. . . . . January, 126–128
McCool, J. I. . . . . October, 451–452
Neagu, R. . . . . July, 338–339

Nelson, L. S. . . . . April, 241–242
Rigdon, S. E. . . . . October, 452–454
Ryan, T. P. . . . . April, 242–243
Ryan, T. P. . . . . July, 339–341
Ryan, T. P. . . . . October, 454–457
Woodall, W. H. . . . . July, 336–338

MISCELLANEOUS

Editorial Collaborators . . . . . October, 462

KEY WORDS

The numbers listed by the key words are the identification numbers assigned to the articles as listed on the previous pages.

Average Run Length; 2, 14
Average Time to Signal; 23
B-Spline; 10
Bayesian Analysis; 21, 28
Bayesian Designs; 19
Bootstrap Simulation Method; 3
Calibration; 29
Censoring; 30
Chi-Squared Distribution; 2
Capability Indices; 12
Combined Array; 25
Computer Experiments; 19
Computer Generated Designs; 11
Concentrated Sampling; 23
Confidence Interval; 3
Consumer's Risk; 28
Control Charts; 14
Coverage Percentage; 3
Cumulative Sum; 14
Cumulative Sum Control Charts; 23
$\mathcal{D}$-Optimality; 9
Degrees of Freedom; 4
Design of Experiments; 9, 27
Desirability Function; 21
Dispersed Sampling; 23
Engine Mapping; 10
EWMA Chart; 30
Exponentially Weighted Moving Average; 26
Exponentially Weighted Moving-Average Control Charts; 23
Factorial Experiment; 10
Fraction of Design Space Plot; 6, 7
Fractional Factorial; 17
$\mathcal{G}$-Optimality; 9
Generalized Likelihood Ratio Test; 13
Generalized Linear Mixed Models; 24
Generalized Linear Models; 19
Heuristic Methods; 20
Hotelling's T^2 Chart; 13
Hypothesis Testing; 12
Latin Squares; 22
Linear Regression; 29
Mixture Experiments; 6, 7, 8, 21, 22, 24
Model Validation; 10
Monte Carlo Simulation; 1
Multiobjective Optimization; 11
Multiple Responses; 19
Multiresponse Optimization; 25
Multivariate Analysis; 5
Multivariate Quality Control; 29
Noise Factors; 18
Nonlinear Regression; 29
Nonregular Fraction; 17
Optimal Design; 10
Orthogonal Array; 17
Orthogonal Blocks; 22
Partial Least Squares; 5
Performance Measure; 15
Preposterior Analysis; 21
Power; 12
Prediction Variance; 8, 27
Process Capability Indices; 3
Process Optimization; 18
Producer's Risk; 28
Proportion Confirming; 21
Quadratic Loss Function; 21, 25
Quadratic Response Surface Models; 22
Quality Control; 2, 5
Quality Engineering; 15
Random Effects; 2
Randomization; 27
Reflecting Boundary EWMA; 30
Regression-Adjusted Chart; 13
Regression Modeling; 20
Relative Standard Deviation; 28
Reliability; 21
Resolution V; 17
Response Feature; 10
Response Surface Desirability Functions; 20
Response Surface Metodology; 7, 11, 18

Ridge Analysis; 21
Robust Parameter Design; 7, 15, 19, 25
Sample Size; 12
Scaled Prediction Variance; 6
Scheffé Quadratic Model; 22
Shewhart Control Charts; 23
Simulation; 21
Six Sigma; 1
Splines; 29
Split-Plot Designs; 9, 19, 24, 27
Stepwise Selection; 16
Stochastic Derivatives; 1
Statistical Process Control; 2, 23, 26, 29
Steady State; 23
Supersaturated Design; 16
Sustained Shift; 23
Three-Quarter Fraction; 17
Tolerance Interval; 28
Transient Shift; 23
Two-Stage Model; 10
Uncertainty; 4
Variance Components; 28
Variance Dispersion Graphs; 6, 7, 8, 19
Wavelets; 29
100% Inspection; 23